

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Christopher L. Wooten, et al.

Serial No.: 09/976,739

Filed: October 11, 2001

Group Art Unit: 2623

Examiner: Kevin Siangchin

RECEIVED

NOV 26 2004

Technology Center 2600

Title: METHOD FOR EVALUATING ANOMALIES IN A SEMICONDUCTOR
MANUFACTURING PROCESS

AMENDMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Madam/Sir:

In response to the Office action mailed August 25, 2004, please amend the
application as follows: